

# 512K x 16 Static RAM

## Features

- **Temperature Ranges**
  - Commercial: 0°C to 70°C
  - Industrial: -40°C to 85°C
  - Automotive: -40°C to 125°C
- **High speed**
  - 55 ns and 70 ns availability
- **Voltage range:**
  - CY62157CV25: 2.2V–2.7V
  - CY62157CV30: 2.7V–3.3V
  - CY62157CV33: 3.0V–3.6V
- **Ultra-low active power**
  - Typical active current: 1.5 mA @ f = 1 MHz
  - Typical active current: 5.5 mA @ f = f<sub>max</sub> (70 ns speed)
- **Low standby power**
- **Easy memory expansion with  $\overline{CE}_1$ ,  $\overline{CE}_2$  and  $\overline{OE}$  features**
- **Automatic power-down when deselected**
- **CMOS for optimum speed/power**

## Functional Description<sup>[1]</sup>

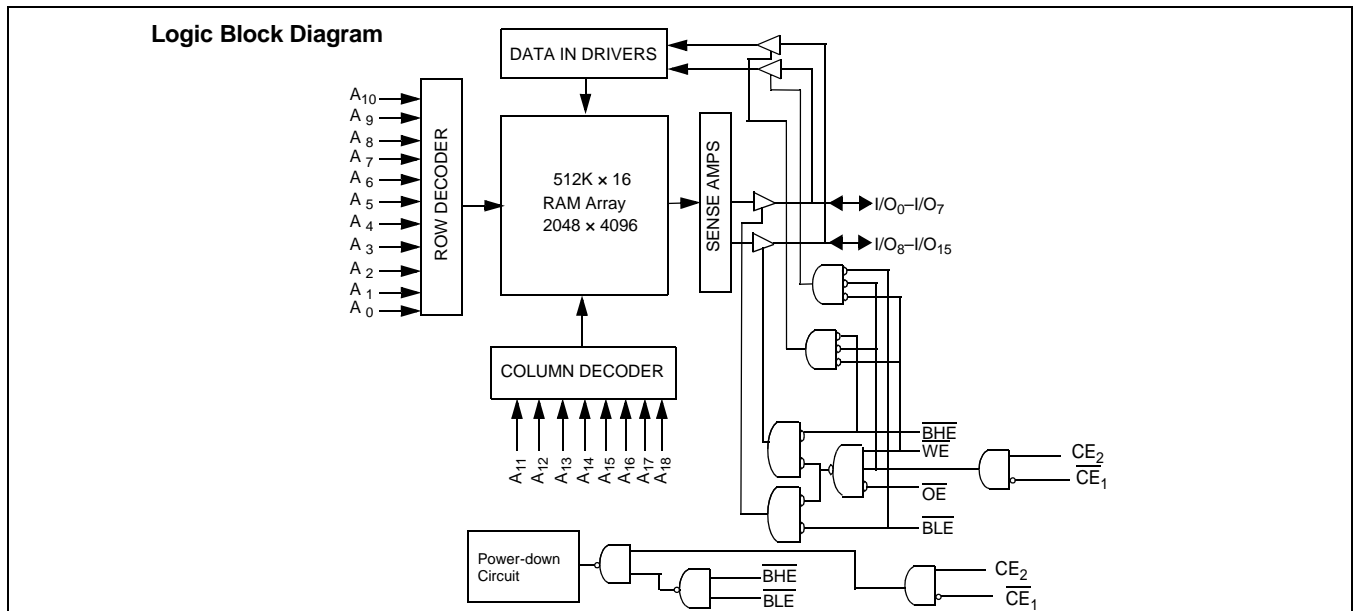
The CY62157CV25/30/33 are high-performance CMOS static RAMs organized as 512K words by 16 bits. These devices feature advanced circuit design to provide ultra-low active current. This is ideal for providing More Battery Life™

(MoBL™) in portable applications such as cellular telephones. The devices also have an automatic power-down feature that significantly reduces power consumption by 80% when addresses are not toggling. The device can also be put into standby mode reducing power consumption by more than 99% when deselected ( $\overline{CE}_1$  HIGH or  $\overline{CE}_2$  LOW or both BLE and BHE are HIGH). The input/output pins (I/O<sub>0</sub> through I/O<sub>15</sub>) are placed in a high-impedance state when: deselected ( $\overline{CE}_1$  HIGH or  $\overline{CE}_2$  LOW), outputs are disabled ( $\overline{OE}$  HIGH), both Byte High Enable and Byte Low Enable are disabled ( $\overline{BHE}$ , BLE HIGH), or during a write operation ( $\overline{CE}_1$  LOW and  $\overline{CE}_2$  HIGH and WE LOW).

Writing to the device is accomplished by taking Chip Enable 1 ( $\overline{CE}_1$ ) and Write Enable (WE) inputs LOW and Chip Enable 2 ( $\overline{CE}_2$ ) HIGH. If Byte Low Enable (BLE) is LOW, then data from I/O pins (I/O<sub>0</sub> through I/O<sub>7</sub>), is written into the location specified on the address pins (A<sub>0</sub> through A<sub>18</sub>). If Byte High Enable (BHE) is LOW, then data from I/O pins (I/O<sub>8</sub> through I/O<sub>15</sub>) is written into the location specified on the address pins (A<sub>0</sub> through A<sub>18</sub>).

Reading from the device is accomplished by taking Chip Enable 1 ( $\overline{CE}_1$ ) and Output Enable ( $\overline{OE}$ ) LOW and Chip Enable 2 ( $\overline{CE}_2$ ) HIGH while forcing the Write Enable (WE) HIGH. If Byte Low Enable (BLE) is LOW, then data from the memory location specified by the address pins will appear on I/O<sub>0</sub> to I/O<sub>7</sub>. If Byte High Enable (BHE) is LOW, then data from memory will appear on I/O<sub>8</sub> to I/O<sub>15</sub>. See the truth table at the back of this data sheet for a complete description of read and write modes.

The CY62157CV25/30/33 are available in a 48-ball FBGA package.

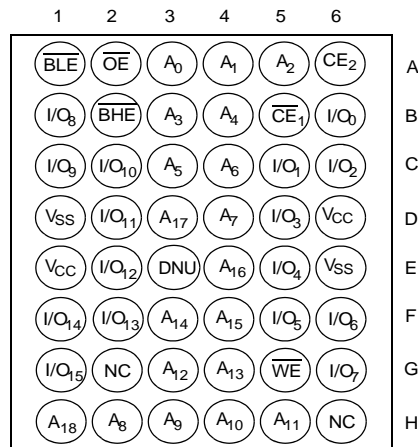


**Note:**

1. For best practice recommendations, please refer to the Cypress application note "System Design Guidelines" on <http://www.cypress.com>.

**Product Portfolio**

Product	Range	V <sub>CC</sub> Range			Speed	Power Dissipation					
						Operating (I <sub>CC</sub> ) mA				Standby (I <sub>SB2</sub> ) μA	
		Min.	Typ. <sup>[2]</sup>	Max.		f = 1 MHz		f = f <sub>max</sub>			
CY62157CV25	Industrial	2.2V	2.5V	2.7V	55 ns	1.5	3	7	15	6	25
	Industrial				70 ns	1.5	3	5.5	12		
CY62157CV30	Industrial	2.7V	3.0V	3.3V	55 ns	1.5	3	7	15	8	25
	Industrial				70 ns	1.5	3	5.5	12	8	25
	Automotive				70 ns					8	70
CY62157CV33	Industrial	3.0V	3.3V	3.6V	55 ns	1.5	3	7	15	10	30
	Industrial				70 ns	1.5	3	5.5	12	10	30
	Automotive				70 ns					10	80

**Pin Configurations<sup>[2, 3, 4]</sup>**
**FBGA (Top View)**

**Pin Definitions**

Name	Definition
Input	<b>A<sub>0</sub>-A<sub>18</sub></b> . Address Inputs
Input/Output	<b>I/O<sub>0</sub>-I/O<sub>15</sub></b> . Data lines. Used as input or output lines depending on operation
Input/Control	<b>WE</b> . Write Enable, Active LOW. When selected LOW, a WRITE is conducted. When selected HIGH, a READ is conducted.
Input/Control	<b>CE<sub>1</sub></b> . Chip Enable 1, Active LOW.
Input/Control	<b>CE<sub>2</sub></b> . Chip Enable 2, Active HIGH.
Input/Control	<b>OE</b> . Output Enable, Active LOW. Controls the direction of the I/O pins. When LOW, the I/O pins behave as outputs. When deasserted HIGH, I/O pins are three-stated, and act as input data pins
Ground	<b>V<sub>SS</sub></b> . Ground for the device
Power Supply	<b>V<sub>CC</sub></b> . Power supply for the device

**Notes:**

- Typical values are included for reference only and are not guaranteed or tested. Typical values are measured at V<sub>CC</sub> = V<sub>CC(typ.)</sub>, T<sub>A</sub> = 25°C.
- NC pins are not connected on the die.
- E3 (DNU) can be left as NC or V<sub>SS</sub> to ensure proper application.

**Maximum Ratings**

(Above which the useful life may be impaired. For user guidelines, not tested.)

Storage Temperature ..... -65°C to +150°C  
 Ambient Temperature with Power Applied.....-55°C to +125°C  
 Supply Voltage to Ground Potential ...-0.5V to  $V_{CCmax} + 0.5V$   
 DC Voltage Applied to Outputs in High-Z State<sup>[5]</sup>.....-0.5V to  $V_{CC} + 0.3V$   
 DC Input Voltage<sup>[5]</sup>.....-0.5V to  $V_{CC} + 0.3V$   
 Output Current into Outputs (LOW) .....20 mA

Static Discharge Voltage..... > 2001V (per MIL-STD-883, Method 3015)

Latch-up Current ..... > 200 mA

**Operating Range**

Device	Range	Ambient Temperature [T <sub>A</sub> ] <sup>[6]</sup>	V <sub>CC</sub>
CY62157CV25	Industrial	-40°C to +85°C	2.2V – 2.7V
CY62157CV30	Industrial	-40°C to +85°C	2.7V – 3.3V
	Automotive	-40°C to +125°C	2.7V – 3.3V
CY62157CV33	Industrial	-40°C to +85°C	3.0V – 3.6V
	Automotive	-40°C to +125°C	3.0V – 3.6V

**Electrical Characteristics Over the Operating Range**

Parameter	Description	Test Conditions	CY62157CV25-55			CY62157CV25-70			Unit
			Min.	Typ. <sup>[2]</sup>	Max.	Min.	Typ. <sup>[2]</sup>	Max.	
V <sub>OH</sub>	Output HIGH Voltage	I <sub>OH</sub> = -0.1 mA V <sub>CC</sub> = 2.2V	2.0			2.0			V
V <sub>OL</sub>	Output LOW Voltage	I <sub>OL</sub> = 0.1 mA V <sub>CC</sub> = 2.2V			0.4			0.4	V
V <sub>IH</sub>	Input HIGH Voltage		1.8		V <sub>CC</sub> + 0.3V	1.8		V <sub>CC</sub> + 0.3V	V
V <sub>IL</sub>	Input LOW Voltage		-0.3		0.6	-0.3		0.6	V
I <sub>IX</sub>	Input Leakage Current	GND ≤ V <sub>I</sub> ≤ V <sub>CC</sub>	-1		+1	-1		+1	μA
I <sub>OZ</sub>	Output Leakage Current	GND ≤ V <sub>O</sub> ≤ V <sub>CC</sub> , Output Disabled	-1		+1	-1		+1	μA
I <sub>CC</sub>	V <sub>CC</sub> Operating Supply Current	f = f <sub>MAX</sub> = 1/t <sub>RC</sub> f = 1 MHz	V <sub>CC</sub> = 2.7V I <sub>OUT</sub> = 0 mA CMOS Levels	7	15		5.5	12	mA
				1.5	3		1.5	3	
I <sub>SB1</sub>	Automatic CE Power-Down Current—CMOS Inputs	CE <sub>1</sub> ≥ V <sub>CC</sub> - 0.2V or CE <sub>2</sub> ≤ 0.2V V <sub>IN</sub> ≥ V <sub>CC</sub> - 0.2V or V <sub>IN</sub> ≤ 0.2V, f = f <sub>max</sub> (Address and Data Only), f = 0 (OE, WE, BHE and BLE)		6	25		6	25	μA
I <sub>SB2</sub>	Automatic CE Power-Down Current—CMOS Inputs	CE <sub>1</sub> ≥ V <sub>CC</sub> - 0.2V or CE <sub>2</sub> ≤ 0.2V V <sub>IN</sub> ≥ V <sub>CC</sub> - 0.2V or V <sub>IN</sub> ≤ 0.2V, f = 0, V <sub>CC</sub> = 2.7V							

**Electrical Characteristics Over the Operating Range**

Parameter	Description	Test Conditions	CY62157CV30-55			CY62157CV30-70			Unit
			Min.	Typ. <sup>[2]</sup>	Max.	Min.	Typ. <sup>[2]</sup>	Max.	
V <sub>OH</sub>	Output HIGH Voltage	I <sub>OH</sub> = -1.0 mA V <sub>CC</sub> = 2.7V	2.4			2.4			V
V <sub>OL</sub>	Output LOW Voltage	I <sub>OL</sub> = 2.1 mA V <sub>CC</sub> = 2.7V			0.4			0.4	V
V <sub>IH</sub>	Input HIGH Voltage		2.2		V <sub>CC</sub> + 0.3V	2.2		V <sub>CC</sub> + 0.3V	V
V <sub>IL</sub>	Input LOW Voltage		-0.3		0.8	-0.3		0.8	V
I <sub>IX</sub>	Input Leakage Current	GND ≤ V <sub>I</sub> ≤ V <sub>CC</sub>	Industrial	-1	+1	-1	+1	μA	
			Automotive			-10	+10	μA	
I <sub>OZ</sub>	Output Leakage Current	GND ≤ V <sub>O</sub> ≤ V <sub>CC</sub> , Output Disabled	Industrial	-1	+1	-1	+1	μA	
			Automotive			-10	+10	μA	
I <sub>CC</sub>	V <sub>CC</sub> Operating Supply Current	f = f <sub>MAX</sub> = 1/t <sub>RC</sub> f = 1 MHz	V <sub>CC</sub> = 3.3V I <sub>OUT</sub> = 0 mA CMOS Levels	7	15		5.5	12	mA
				1.5	3		1.5	3	

**Notes:**

- V<sub>IL(min.)</sub> = -2.0V for pulse durations less than 20 ns.
- T<sub>A</sub> is the "Instant-On" case temperature.

**Electrical Characteristics** Over the Operating Range (continued)

Parameter	Description	Test Conditions	CY62157CV30-55			CY62157CV30-70			Unit	
			Min.	Typ. <sup>[2]</sup>	Max.	Min.	Typ. <sup>[2]</sup>	Max.		
I <sub>SB1</sub>	Automatic CE Power-Down Current—CMOS Inputs	CE <sub>1</sub> ≥ V <sub>CC</sub> - 0.2V or CE <sub>2</sub> ≤ 0.2V V <sub>IN</sub> ≥ V <sub>CC</sub> - 0.2V or V <sub>IN</sub> ≤ 0.2V, f = f <sub>max</sub> (Address and Data Only), f = 0 (OE, WE, BHE and BLE)	Industrial		8	25		8	25	μA
			Automotive					8	70	μA
I <sub>SB2</sub>	Automatic CE Power-Down Current—CMOS Inputs	CE <sub>1</sub> ≥ V <sub>CC</sub> - 0.2V or CE <sub>2</sub> ≤ 0.2V V <sub>IN</sub> ≥ V <sub>CC</sub> - 0.2V or V <sub>IN</sub> ≤ 0.2V, f = 0, V <sub>CC</sub> = 3.3V	Industrial		8	25		8	25	μA
			Automotive					8	70	μA

**Electrical Characteristics** Over the Operating Range

Parameter	Description	Test Conditions	CY62157CV33-55			CY62157CV33-70			Unit		
			Min.	Typ. <sup>[2]</sup>	Max.	Min.	Typ. <sup>[2]</sup>	Max.			
V <sub>OH</sub>	Output HIGH Voltage	I <sub>OH</sub> = -1.0 mA	V <sub>CC</sub> = 3.0V		2.4			2.4		V	
V <sub>OL</sub>	Output LOW Voltage	I <sub>OL</sub> = 2.1 mA	V <sub>CC</sub> = 3.0V					0.4		V	
V <sub>IH</sub>	Input HIGH Voltage				2.2		V <sub>CC</sub> + 0.3V	2.2		V <sub>CC</sub> + 0.3V	
V <sub>IL</sub>	Input LOW Voltage				-0.3			-0.3		V	
I <sub>IX</sub>	Input Leakage Current	GND ≤ V <sub>I</sub> ≤ V <sub>CC</sub>	Industrial		-1		+1	-1		+1	μA
			Automotive					-10		+10	μA
I <sub>OZ</sub>	Output Leakage Current	GND ≤ V <sub>O</sub> ≤ V <sub>CC</sub> , Output Disabled	Industrial		-1		+1	-1		+1	μA
			Automotive					-10		+10	μA
I <sub>CC</sub>	V <sub>CC</sub> Operating Supply Current	f = f <sub>MAX</sub> = 1/t <sub>RC</sub>	V <sub>CC</sub> = 3.6V					5.5	12	mA	
		f = 1 MHz	I <sub>OUT</sub> = 0 mA CMOS Levels					1.5	3		
I <sub>SB1</sub>	Automatic CE Power-Down Current—CMOS Inputs	CE <sub>1</sub> ≥ V <sub>CC</sub> - 0.2V or CE <sub>2</sub> ≤ 0.2V V <sub>IN</sub> ≥ V <sub>CC</sub> - 0.2V or V <sub>IN</sub> ≤ 0.2V, f = f <sub>max</sub> (Address and Data Only), f = 0 (OE, WE, BHE, and BLE)	Industrial		10	30		10	30	μA	
			Automotive					10	80	μA	
I <sub>SB2</sub>	Automatic CE Power-Down Current—CMOS Inputs	CE <sub>1</sub> ≥ V <sub>CC</sub> - 0.2V or CE <sub>2</sub> ≤ 0.2V V <sub>IN</sub> ≥ V <sub>CC</sub> - 0.2V or V <sub>IN</sub> ≤ 0.2V, f = 0, V <sub>CC</sub> = 3.6V	Industrial		10	30		10	30	μA	
			Automotive					10	80	μA	

**Thermal Resistance**

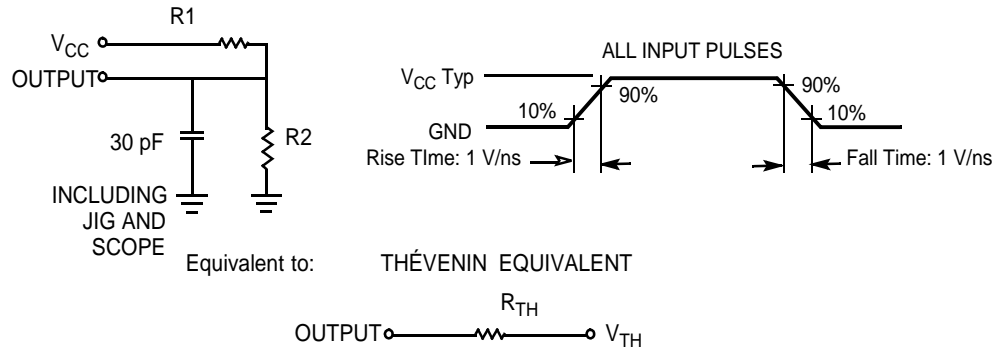
Parameter	Description	Test Conditions	BGA	Unit
Θ <sub>JA</sub>	Thermal Resistance (Junction to Ambient) <sup>[7]</sup>	Still Air, soldered on a 3 x 4.5 inch, two-layer printed circuit board	55	°C/W
Θ <sub>JC</sub>	Thermal Resistance (Junction to Case) <sup>[7]</sup>		16	°C/W

**Note:**

7. Tested initially and after any design or process changes that may affect these parameters.

**Capacitance<sup>[7]</sup>**

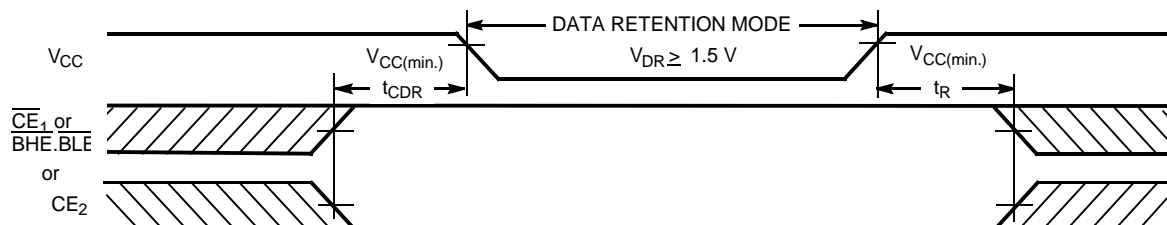
Parameter	Description	Test Conditions	Max.	Unit
$C_{IN}$	Input Capacitance	$T_A = 25^\circ\text{C}$ , $f = 1\text{ MHz}$ , $V_{CC} = V_{CC(\text{typ.})}$	6	pF
$C_{OUT}$	Output Capacitance		8	pF

**AC Test Loads and Waveforms**


Parameters	2.5V	3.0V	3.3V	Unit
R1	16.6	1.105	1.216	$\text{K}\Omega$
R2	15.4	1.550	1.374	$\text{K}\Omega$
$R_{TH}$	8.0	0.645	0.645	$\text{K}\Omega$
$V_{TH}$	1.20	1.75	1.75	V

**Data Retention Characteristics (Over the Operating Range)**

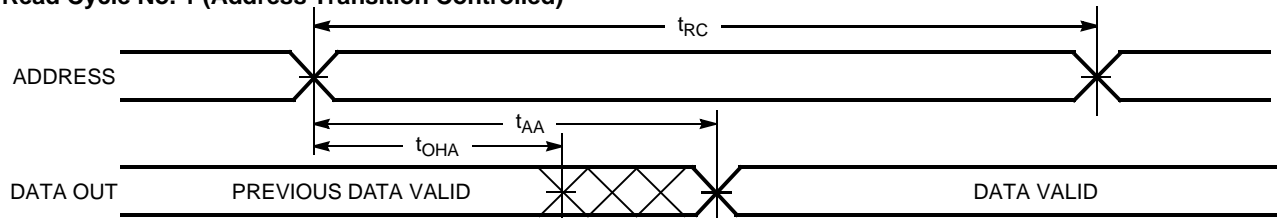
Parameter	Description	Conditions	Min.	Typ. <sup>[2]</sup>	Max.	Unit
$V_{DR}$	$V_{CC}$ for Data Retention		1.5			V
$I_{CCDR}$	Data Retention Current	$V_{CC} = 1.5\text{V}$ , $\overline{CE}_1 \geq V_{CC} - 0.2\text{V}$ or $\overline{CE}_2 \leq 0.2\text{V}$ , $V_{IN} \geq V_{CC} - 0.2\text{V}$ or $V_{IN} \leq 0.2\text{V}$	Industrial	4	20	$\mu\text{A}$
			Automotive	4	60	$\mu\text{A}$
$t_{CDR}^{[8]}$	Chip Deselect to Data Retention Time		0			ns
$t_R^{[8]}$	Operation Recovery Time		$t_{RC}$			ns

**Data Retention Waveform<sup>[9]</sup>**

**Notes:**

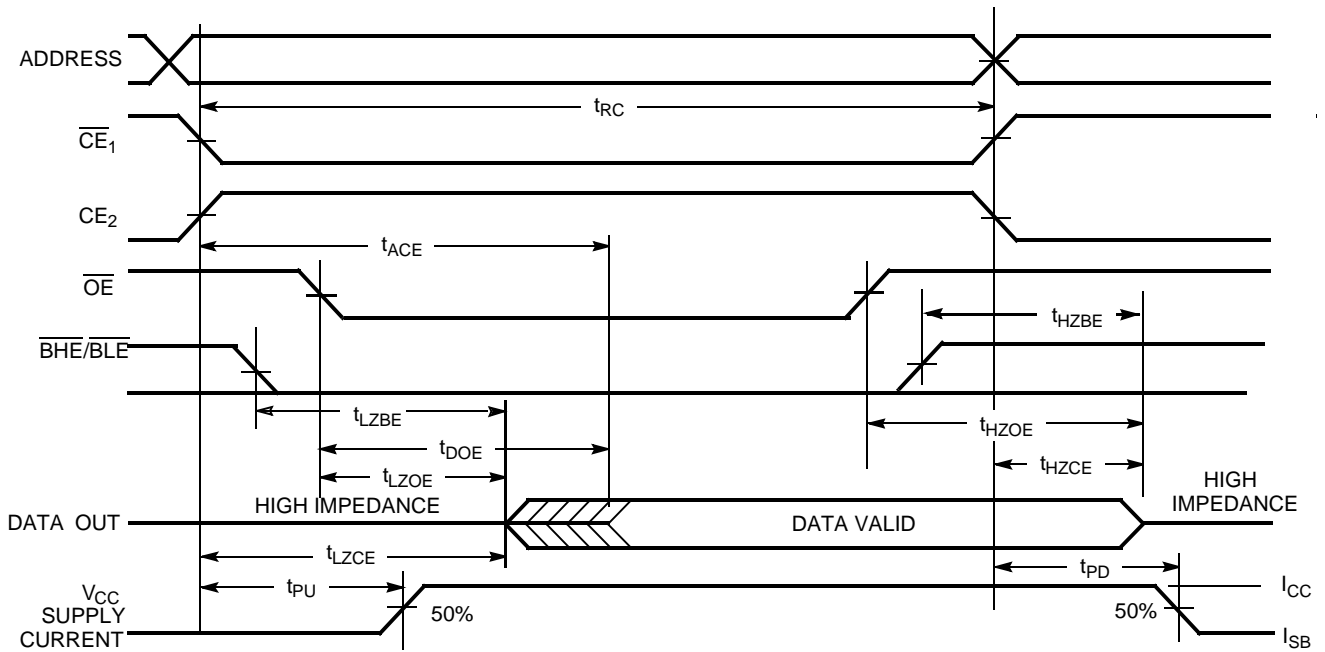
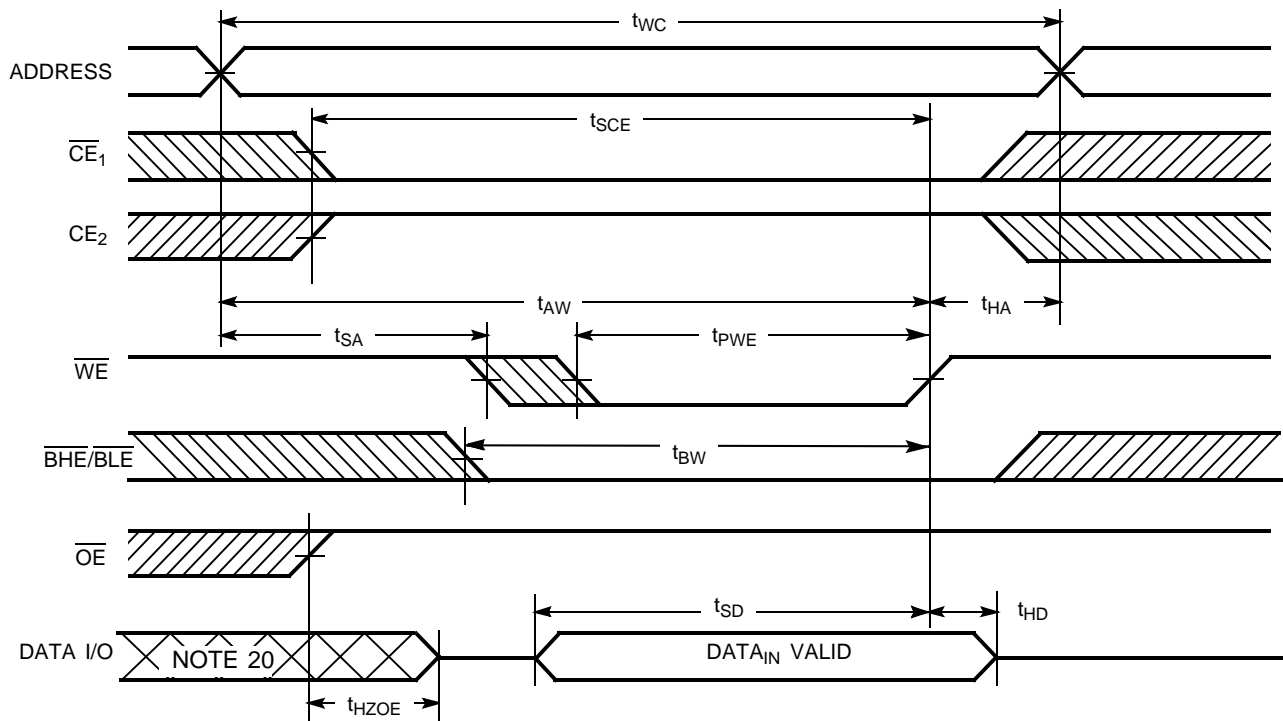
- Full Device AC operation requires linear  $V_{CC}$  ramp from  $V_{DR}$  to  $V_{CC(\text{min.})} > 100\ \mu\text{s}$  or stable at  $V_{CC(\text{min.})} > 100\ \mu\text{s}$ .
- $\overline{BHE.BLE}$  is the AND of both  $\overline{BHE}$  and  $\overline{BLE}$ . Chip can be deselected by either disabling the chip enable signals or by disabling both  $\overline{BHE}$  and  $\overline{BLE}$ .

**Switching Characteristics** Over the Operating Range <sup>[10]</sup>

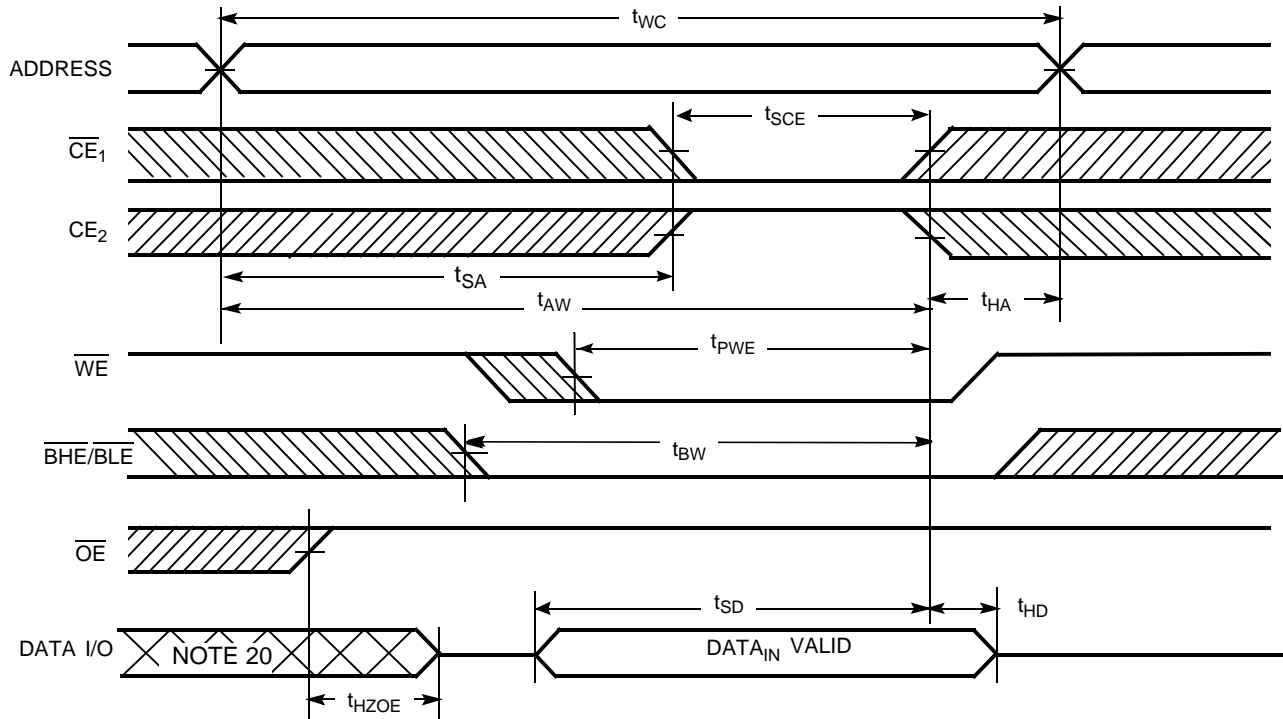
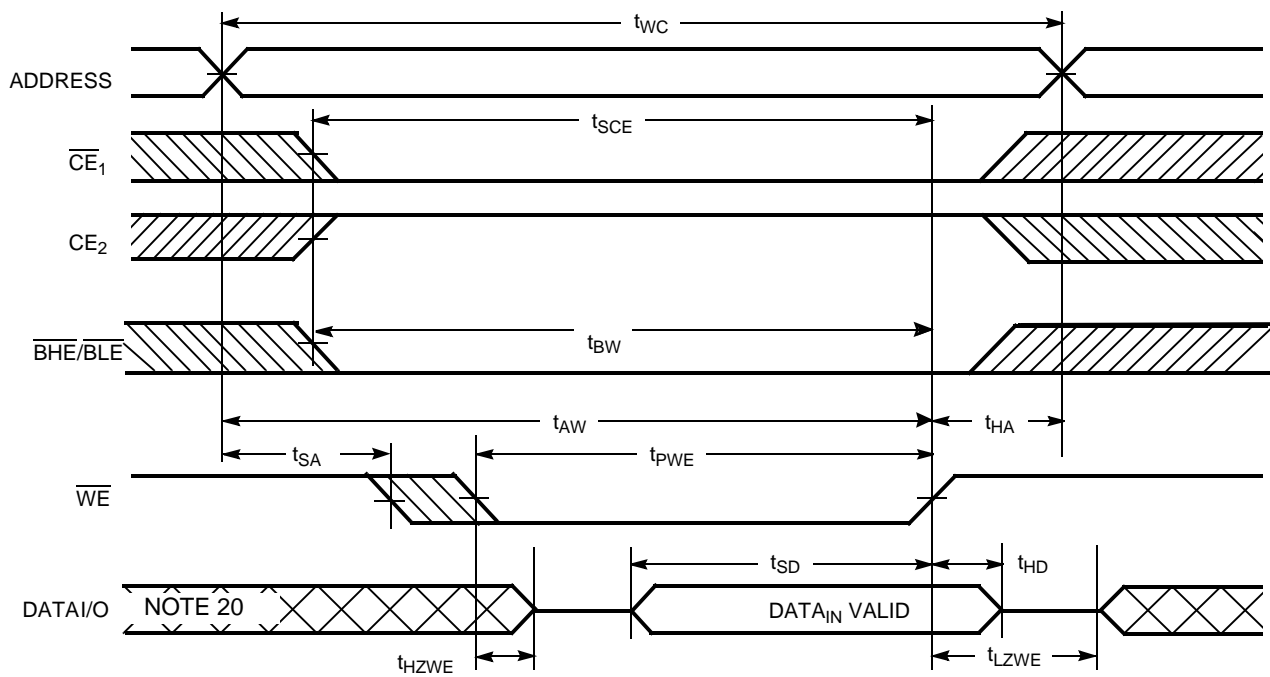
Parameter	Description	55 ns		70 ns		Unit
		Min.	Max.	Min.	Max.	
<b>Read Cycle</b>						
$t_{RC}$	Read Cycle Time	55		70		ns
$t_{AA}$	Address to Data Valid		55		70	ns
$t_{OHA}$	Data Hold from Address Change	10		10		ns
$t_{ACE}$	$\overline{CE}_1$ LOW and $\overline{CE}_2$ HIGH to Data Valid		55		70	ns
$t_{DOE}$	OE LOW to Data Valid		25		35	ns
$t_{LZOE}$	OE LOW to Low-Z <sup>[11]</sup>	5		5		ns
$t_{HZOE}$	OE HIGH to High-Z <sup>[11, 12]</sup>		20		25	ns
$t_{LZCE}$	$\overline{CE}_1$ LOW and $\overline{CE}_2$ HIGH to Low-Z <sup>[11]</sup>	10		10		ns
$t_{HZCE}$	$\overline{CE}_1$ HIGH or $\overline{CE}_2$ LOW to High-Z <sup>[11, 12]</sup>		20		25	ns
$t_{PU}$	$\overline{CE}_1$ LOW and $\overline{CE}_2$ HIGH to Power-up	0		0		ns
$t_{PD}$	$\overline{CE}_1$ HIGH or $\overline{CE}_2$ LOW to Power-down		55		70	ns
$t_{DBE}$	BHE/ $\overline{BLE}$ LOW to Data Valid		55		70	ns
$t_{LZBE}^{[11]}$	BHE/ $\overline{BLE}$ LOW to Low-Z <sup>[13]</sup>	5		5		ns
$t_{HZBE}$	BHE/ $\overline{BLE}$ HIGH to High-Z <sup>[11, 12]</sup>		20		25	ns
<b>Write Cycle<sup>[14]</sup></b>						
$t_{WC}$	Write Cycle Time	55		70		ns
$t_{SCE}$	$\overline{CE}_1$ LOW and $\overline{CE}_2$ HIGH to Write End	45		60		ns
$t_{AW}$	Address Set-up to Write End	45		60		ns
$t_{HA}$	Address Hold from Write End	0		0		ns
$t_{SA}$	Address Set-up to Write Start	0		0		ns
$t_{PWE}$	$\overline{WE}$ Pulse Width	45		50		ns
$t_{BW}$	BHE/ $\overline{BLE}$ Pulse Width	50		60		ns
$t_{SD}$	Data Set-up to Write End	25		30		ns
$t_{HD}$	Data Hold from Write End	0		0		ns
$t_{HZWE}$	$\overline{WE}$ LOW to High-Z <sup>[11, 12]</sup>		20		25	ns
$t_{LZWE}$	$\overline{WE}$ HIGH to Low-Z <sup>[11]</sup>	5		5		ns

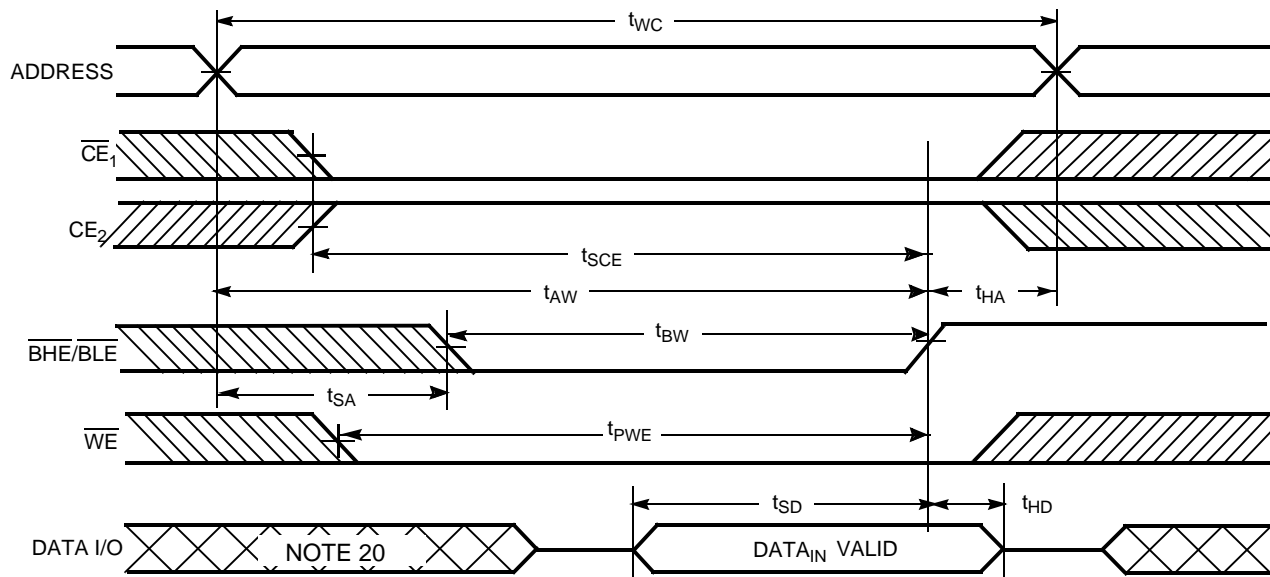
**Switching Waveforms**
**Read Cycle No. 1 (Address Transition Controlled)<sup>[15, 16]</sup>**

**Notes:**

- Test conditions assume signal transition time of 5 ns or less, timing reference levels of  $V_{CC(typ.)}/2$ , input pulse levels of 0 to  $V_{CC(typ.)}$ , and output loading of the specified  $I_{OL}/I_{OH}$  and 30-pF load capacitance.
- At any given temperature and voltage condition,  $t_{HZCE}$  is less than  $t_{LZCE}$ ,  $t_{HZBE}$  is less than  $t_{LZBE}$ ,  $t_{HZOE}$  is less than  $t_{LZOE}$ , and  $t_{HZWE}$  is less than  $t_{LZWE}$  for any given device.
- $t_{HZOE}$ ,  $t_{HZCE}$ ,  $t_{HZBE}$ , and  $t_{HZWE}$  transitions are measured when the outputs enter a high-impedance state.
- When both byte enables are toggled together this value is 10 ns.
- The internal Write time of the memory is defined by the overlap of  $\overline{WE}$ ,  $\overline{CE}_1 = V_{IL}$ ,  $\overline{BHE}$  and/or  $\overline{BLE} = V_{IL}$ ,  $\overline{CE}_2 = V_{IH}$ . All signals must be ACTIVE to initiate a Write and any of these signals can terminate a Write by going INACTIVE. The data input set-up and hold timing should be referenced to the edge of the signal that terminates the Write.
- Device is continuously selected.  $\overline{OE}$ ,  $\overline{CE}_1 = V_{IL}$ ,  $\overline{BHE}$  and/or  $\overline{BLE} = V_{IL}$ ,  $\overline{CE}_2 = V_{IH}$ .
- $\overline{WE}$  is HIGH for Read cycle.

**Switching Waveforms (continued)**
**Read Cycle No. 2 ( $\overline{OE}$  Controlled)** [16, 17]

**Write Cycle No. 1 ( $\overline{WE}$  Controlled)** [14, 18, 19]

**Notes:**

17. Address valid prior to or coincident with  $\overline{CE}_1$ ,  $\overline{BHE}$ ,  $\overline{BLE}$  transition LOW and  $CE_2$  transition HIGH.
18. Data I/O is high-impedance if  $\overline{OE} = V_{IH}$ .
19. If  $\overline{CE}_1$  goes HIGH or  $CE_2$  goes LOW simultaneously with  $\overline{WE}$  HIGH, the output remains in a high-impedance state.
20. During this period, the I/Os are in output state and input signals should not be applied.

**Switching Waveforms (continued)**
**Write Cycle No. 2 ( $\overline{CE}_1$  or  $\overline{CE}_2$  Controlled) [14, 18, 19]**

**Write Cycle No. 3 ( $\overline{WE}$  Controlled,  $\overline{OE}$  LOW) [19]**


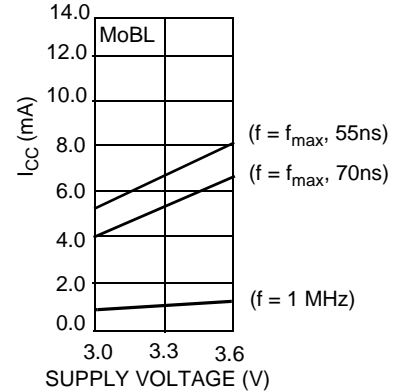
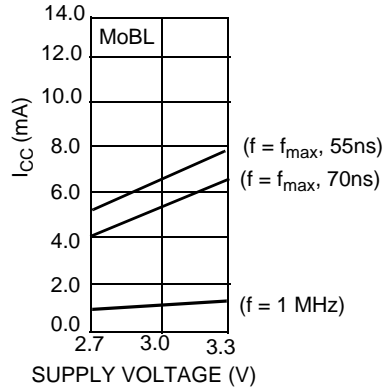
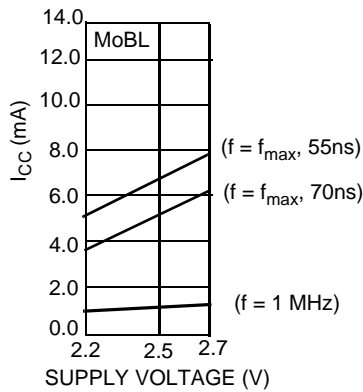
**Switching Waveforms (continued)**
**Write Cycle No. 4 ( $\overline{\text{BHE}}/\overline{\text{BLE}}$  Controlled,  $\overline{\text{OE}}$  LOW)<sup>[19]</sup>**

**Truth Table**

$\overline{\text{CE}}_1$	$\overline{\text{CE}}_2$	$\overline{\text{WE}}$	$\overline{\text{OE}}$	$\overline{\text{BHE}}$	$\overline{\text{BLE}}$	Inputs/Outputs	Mode	Power
H	X	X	X	X	X	High Z	Deselect/Power-Down	Standby ( $I_{\text{SB}}$ )
X	L	X	X	X	X	High Z	Deselect/Power-Down	Standby ( $I_{\text{SB}}$ )
X	X	X	X	H	H	High Z	Deselect/Power-Down	Standby ( $I_{\text{SB}}$ )
L	H	H	L	L	L	Data Out ( $I/O_0$ – $I/O_{15}$ )	Read	Active ( $I_{\text{CC}}$ )
L	H	H	L	H	L	Data Out ( $I/O_0$ – $I/O_7$ ); $I/O_8$ – $I/O_{15}$ in High Z	Read	Active ( $I_{\text{CC}}$ )
L	H	H	L	L	H	Data Out ( $I/O_8$ – $I/O_{15}$ ); $I/O_0$ – $I/O_7$ in High Z	Read	Active ( $I_{\text{CC}}$ )
L	H	H	H	L	L	High Z	Output Disabled	Active ( $I_{\text{CC}}$ )
L	H	H	H	H	L	High Z	Output Disabled	Active ( $I_{\text{CC}}$ )
L	H	H	H	L	H	High Z	Output Disabled	Active ( $I_{\text{CC}}$ )
L	H	L	X	L	L	Data In ( $I/O_0$ – $I/O_{15}$ )	Write	Active ( $I_{\text{CC}}$ )
L	H	L	X	H	L	Data In ( $I/O_0$ – $I/O_7$ ); $I/O_8$ – $I/O_{15}$ in High Z	Write	Active ( $I_{\text{CC}}$ )
L	H	L	X	L	H	Data In ( $I/O_8$ – $I/O_{15}$ ); $I/O_0$ – $I/O_7$ in High Z	Write	Active ( $I_{\text{CC}}$ )

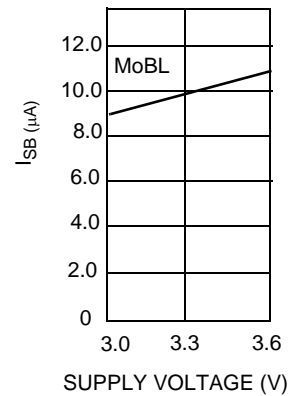
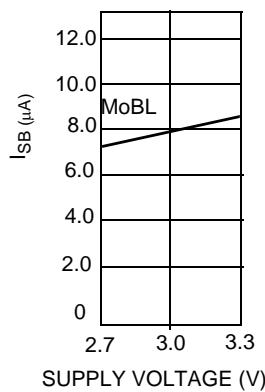
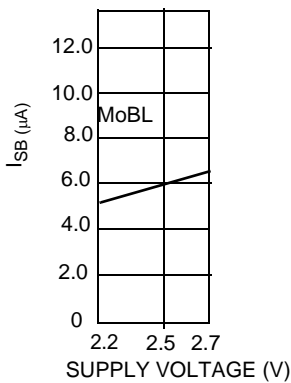
### Typical DC and AC Characteristics

(Typical values are included for reference only and are not guaranteed or tested. Typical values are measured at  $V_{CC} = V_{CC(typ)}$ ,  $T_A = 25^\circ\text{C}$ .)

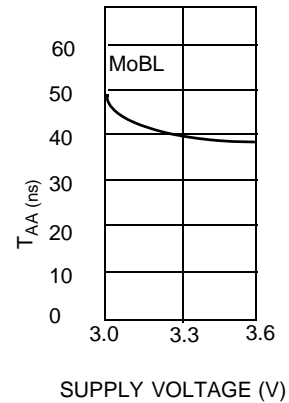
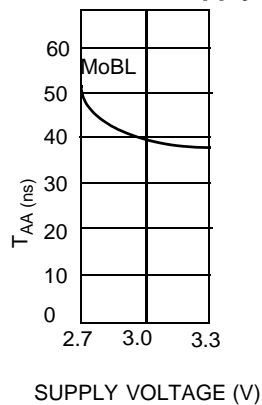
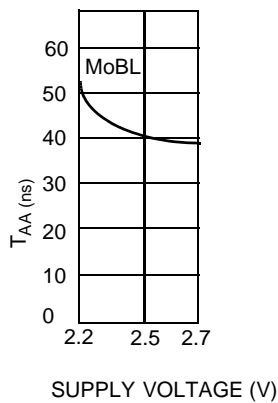
#### Operating Current vs. Supply Voltage



#### Standby Current vs. Supply Voltage



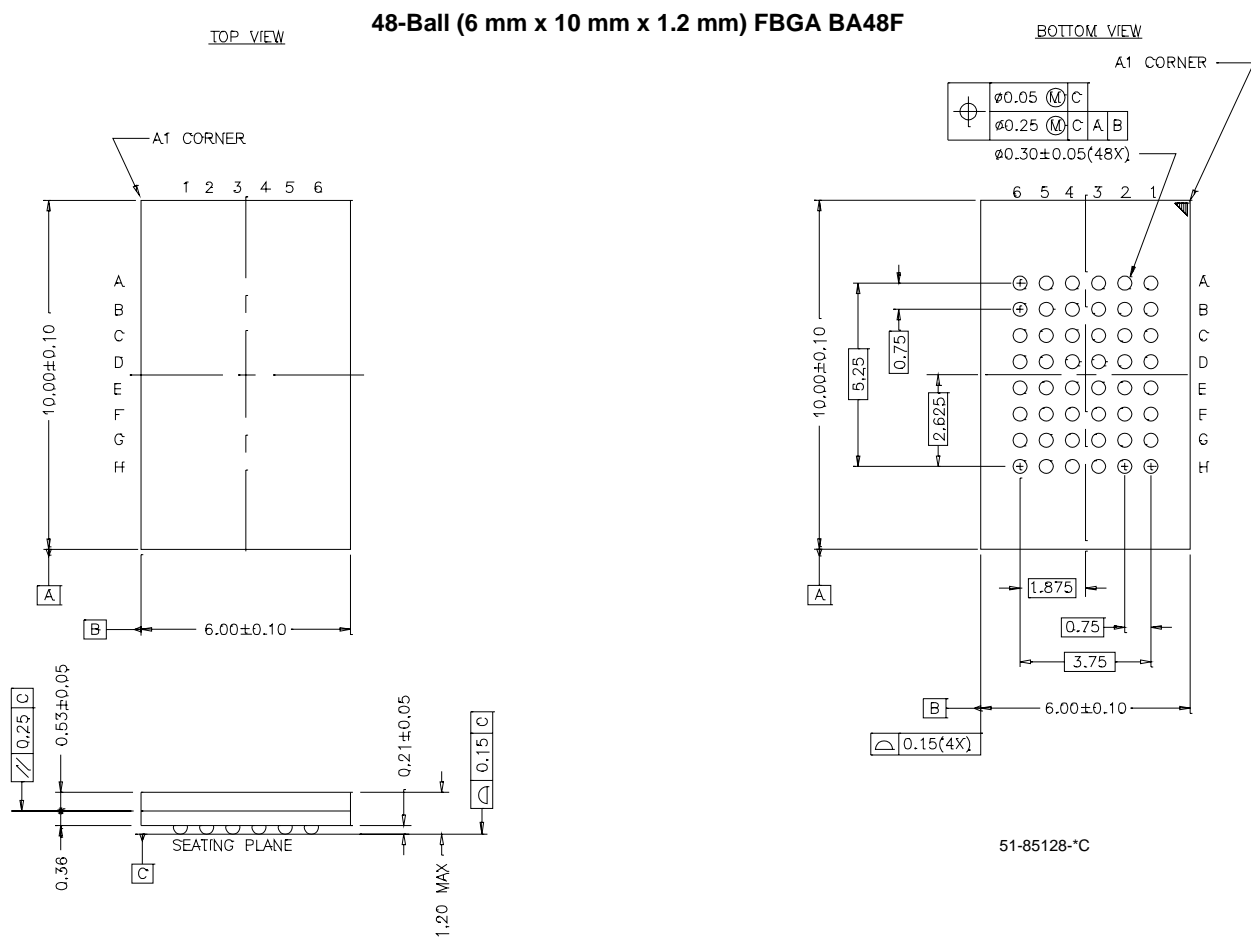
#### Access Time vs. Supply Voltage



**Ordering Information**

Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
55	CY62157CV25LL-55BAI	BA48F	48-ball Fine-pitch BGA	Industrial
	CY62157CV30LL-55BAI			
	CY62157CV33LL-55BAI			
70	CY62157CV25LL-70BAI			Industrial
	CY62157CV30LL-70BAI			Industrial
	CY62157CV30LL-70BAE			Automotive
	CY62157CV33LL-70BAI	Industrial		
	CY62157CV33LL-70BAE	Automotive		

**Package Diagram**



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**Document History Page**

Document Title: CY62157CV25/30/33 512K x 16 Static Ram				
Document Number: 38-05014				
REV.	ECN NO.	Issue Date	Orig. of Change	Description of Change
**	106184	05/10/01	HRT/MGN	New data sheet – Advance Information
*A	107241	07/24/01	MGN	Made corrections to Advance Information Added 55 ns bin
*B	109621	03/11/02	MGN	Changed from Advance Information to Final
*C	114218	05/01/02	GUG/MGN	Improved Typical and Max I <sub>CC</sub> values
*D	238448	See ECN	AJU	Added Automotive Product information
*E	269729	See ECN	SYT	Added Automotive Product information for CY62157CV30 – 70 ns Added I <sub>LX</sub> and I <sub>OZ</sub> values for Automotive range of CY62157CV33 – 70 ns



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